

PTO/SB/08A LIST OF PATENTS AND PUBLICATIONS FOR APPLICANT'S INFORMATION DISCLOSURE STATEMENT (Use several sheets if necessary)	ATTY. DOCKET NO. JEV/KAR:1016.2019	SERIAL NO. 10/678549
	APPLICANT Randy J. Schwindt et al.	
	FILING DATE Herewith 10/02/03	GROUP 2829

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

E.P.K.	BB	Micromanipulator Company, Inc., "Test Station Accessories." (1983) (month unavailable)
E.P.K.	BC	Micromanipulator Company, Inc., "Model 8000 Test Station." (1986) (month unavailable)
E.P.K.	BD	"Model TPO3000 Series Thermochuck® Systems," four-page product note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
	BE	
E.P.K.	BF	"Application Note 1 Controlled Environment Enclosure," two-page application note, Temptronic Corporation, Newton, MA (May 1992 or earlier)
E.P.K.	BG	Micromanipulator Company, Inc. "Model 8000 Test Station." (1988) (month unavailable)
E.P.K.	BH	Applebay, Harry F. Deposition transcript (pp. 61-67) with exhibits 581 A.B.C. describing Flexion AP-1 probe station sold in 1987 (May 1988)
E.P.K.	BI	"Cross Section Signatone S-1240," one-page sketch prepared by Signatone counsel, Feb. 1988
E.P.K.	BJ	"S-1240," two-page product note, Signatone, San Jose, CA (February 1988 or earlier per Signatone counsel)
E.P.K.	BK	Y. Yamamoto, "A Compact Self-Shielding Prober..." IEEE Trans., Inst. and Meas., Vol. 38, pp. 1088-1093 (1989) Dec.
E.P.K.	BL	Temptronic's "Guarded" Chuck, one-page note describing guarding system of Temptronic Corporation of Newton, MA, dated 11/15/89.
E.P.K.	BM	Beck & Tomann, "Chip Tester," IBM Technical Disclosure Bulletin, p. 4819 (January 1985).
E.P.K.	BN	Article by William Knauer entitled "Fixturing for Low-Current/Low Voltage Parametric Testing," appearing in Evaluation Engineering, (1990), pp. 150-153 Nov.
E.P.K.	BO	Hewlett-Packard, "Application Note 356-HP 4142B Modular DC Source/Monitor Practical Application," (Nov. 1987), pp. 1-4
E.P.K.	BP	Hewlett-Packard, H-P Model 4284A Precision LCR Meter, Operation Manual (December 1991) pp. 1-2, 6-9 and 6-15

EXAMINER Ernst P. Karden	DATE CONSIDERED 1/09/05
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EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.